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INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application Number	09/483881		
APR 2 5 2003	Filing Date	January 18, 2000		
	First Named Inventor	Ahn, Kie		
	Group Art Unit	2812		
1 9	Examiner Name	Nguyen, Ha		
The Shant of 1	Attorney Docket No: 303.672US1			

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